

Search Notes

Application/Control No.

10/626,726

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

NISHIO ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	3/27/2007	NT
348/241, 252, 253 (text search - see search history printout)	3/27/2007	NT
text search all classes 348 and 382 - see search history printout	5/2/2007	NT
Inventorship search - see search history printout	5/4/2007	NT